



ALPHA & OMEGA
SEMICONDUCTOR

AOSP21321
30V P-Channel MOSFET

General Description

- Latest Advanced Trench Technology
- Low $R_{DS(ON)}$
- High Current Capability
- RoHS and Halogen-Free Compliant

Product Summary

V_{DS}	-30V
I_D (at $V_{GS}=-10V$)	-11A
$R_{DS(ON)}$ (at $V_{GS}=-10V$)	< 17mΩ
$R_{DS(ON)}$ (at $V_{GS}=-4.5V$)	< 30mΩ

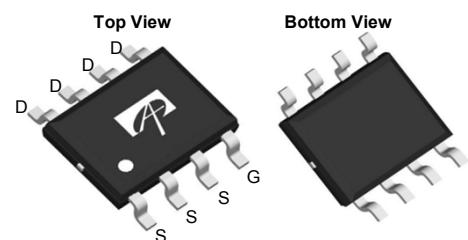
Applications

- Notebook AC-in Load Switch
- Battery Protection Charge/Discharge

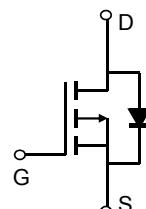
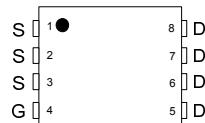
100% UIS Tested
100% R_g Tested



SOIC-8



Top View



Orderable Part Number

AOSP21321

Package Type

SO-8

Form

Tape & Reel

Minimum Order Quantity

3000

Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	-30	V
Gate-Source Voltage	V_{GS}	± 25	V
Continuous Drain Current	I_D	-11	A
$T_A=70^\circ C$		-8.5	
Pulsed Drain Current ^C	I_{DM}	-44	
Avalanche Current ^C	I_{AS}	25	A
Avalanche energy $L=0.1\text{mH}$ ^C	E_{AS}	31	mJ
Power Dissipation ^B	P_D	3.1	W
$T_A=70^\circ C$		2.0	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	31	40	°C/W
Maximum Junction-to-Ambient ^{A,D} Steady-State		59	75	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	16	24	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}$, $V_{GS}=0\text{V}$	-30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-30\text{V}$, $V_{GS}=0\text{V}$			-1	μA
				$T_J=55^\circ\text{C}$		-5
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}$, $V_{GS}=\pm25\text{V}$			±100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=-250\mu\text{A}$	-1.3	-1.8	-2.3	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}$, $I_D=-11\text{A}$		14	17	$\text{m}\Omega$
				$T_J=125^\circ\text{C}$	20	24
		$V_{GS}=-4.5\text{V}$, $I_D=-8\text{A}$			23.5	30
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}$, $I_D=-11\text{A}$			25	S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}$, $V_{GS}=0\text{V}$			-0.72	-1
I_S	Maximum Body-Diode Continuous Current				-4	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}$, $V_{DS}=-15\text{V}$, $f=1\text{MHz}$		1180		pF
C_{oss}	Output Capacitance			185		pF
C_{rss}	Reverse Transfer Capacitance			155		pF
R_g	Gate resistance	$f=1\text{MHz}$		5	10	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=-10\text{V}$, $V_{DS}=-15\text{V}$, $I_D=-11\text{A}$		21	34	nC
$Q_g(4.5\text{V})$	Total Gate Charge			11	18	nC
Q_{gs}	Gate Source Charge			6		nC
Q_{gd}	Gate Drain Charge			3		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=-10\text{V}$, $V_{DS}=-15\text{V}$, $R_L=1.3\Omega$, $R_{\text{GEN}}=3\Omega$		10.5		ns
t_r	Turn-On Rise Time			8.5		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			30		ns
t_f	Turn-Off Fall Time			11.5		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-11\text{A}$, $di/dt=500\text{A}/\mu\text{s}$		10		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-11\text{A}$, $di/dt=500\text{A}/\mu\text{s}$		15		nC

A. The value of R_{QA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

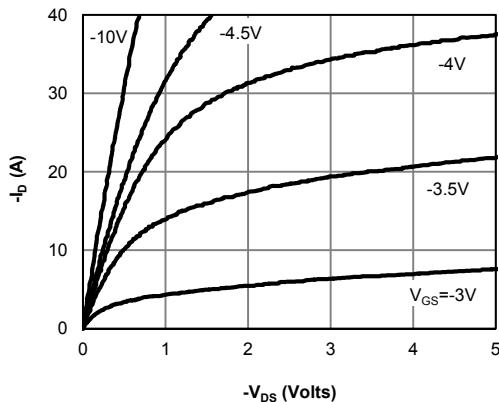
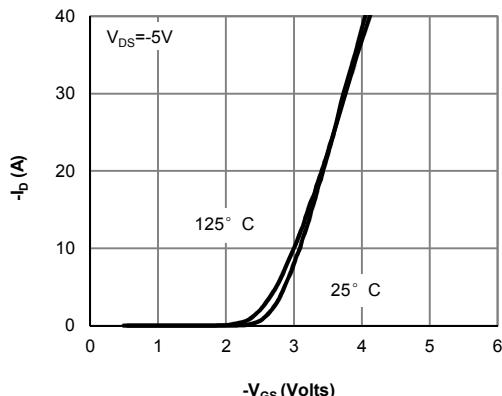
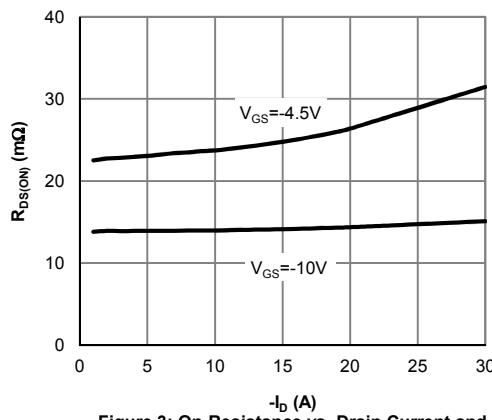
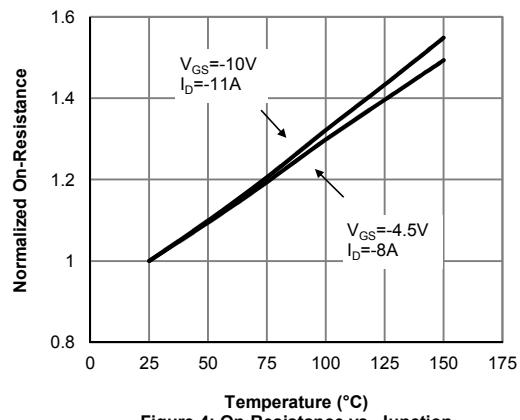
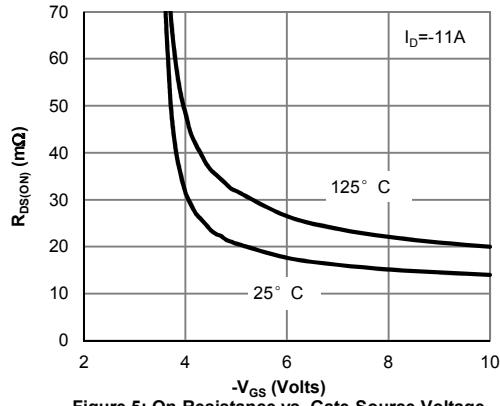
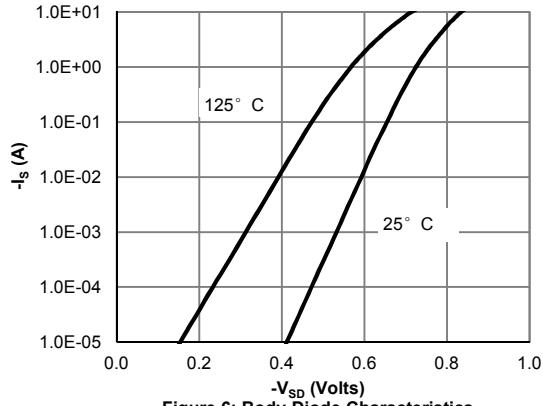
C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

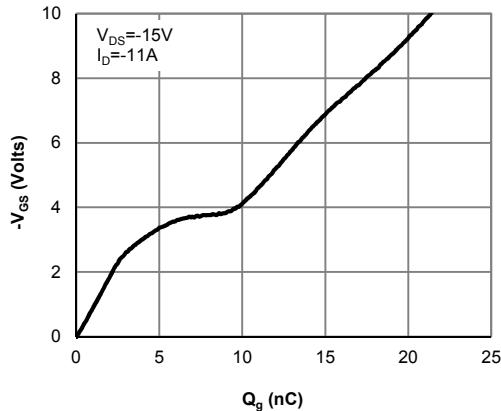
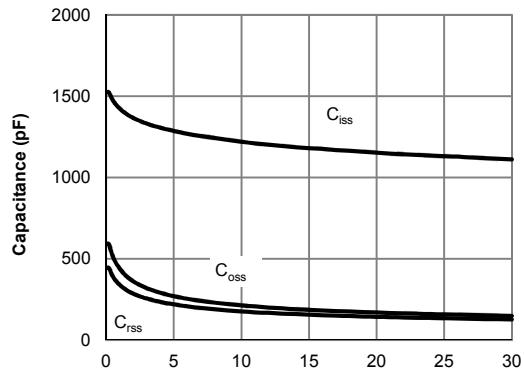
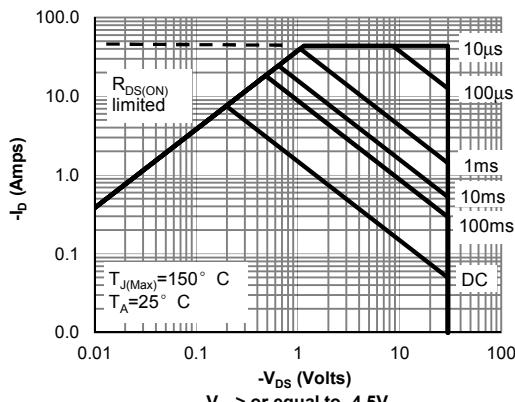
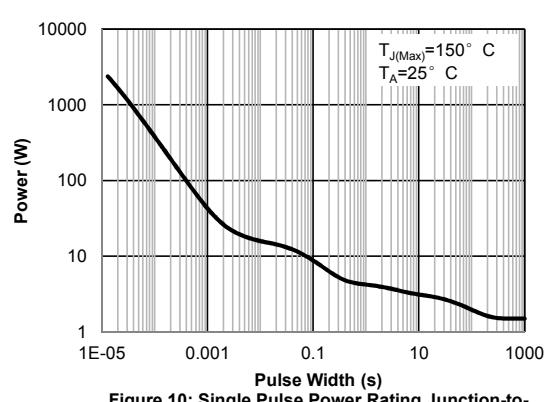
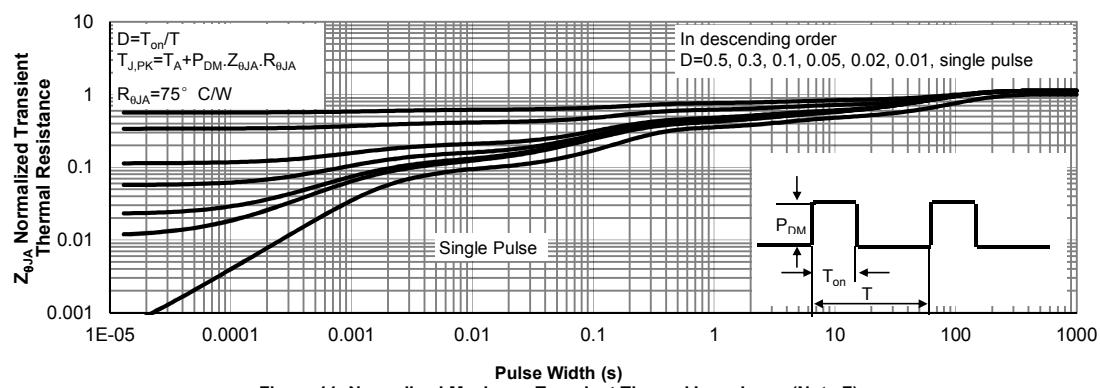
D. The R_{QA} is the sum of the thermal impedance from junction to lead R_{JL} and lead to ambient.

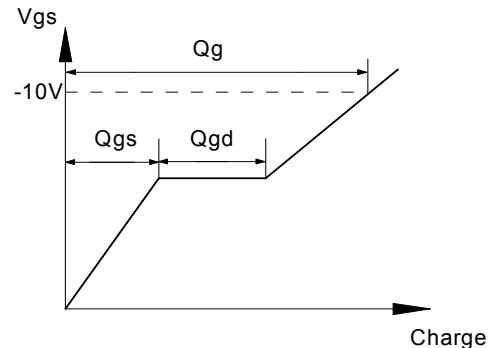
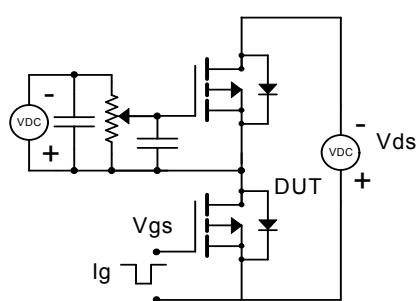
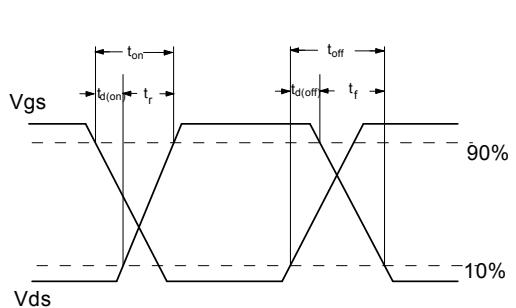
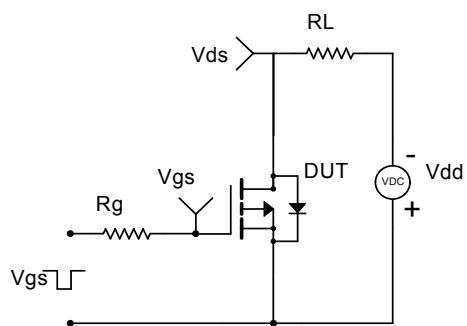
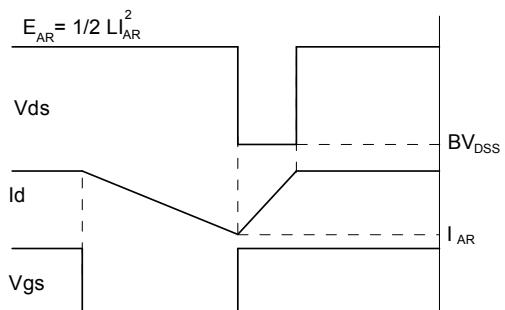
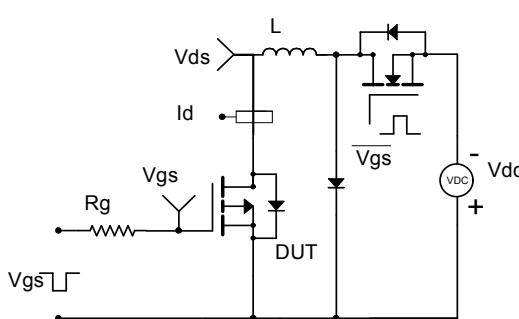
E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
